



中国认可 国际互认 检测 TESTING CNAS L5488

Page 1 of 55

EMC Test Report

Report No.: AGC02862190602EE03

PRODUCT DESIGNATION		Portable CD Player
BRAND NAME	;	LEXIBOOK
MODEL NAME	:	RCD108
APPLICANT	:	LEXIBOOK LIMITED
DATE OF ISSUE		Jul. 08, 2019
STANDARD(S)	3	EN 55032:2015/AC: 2016 EN 61000-3-2:2014 EN 61000-3-3:2013 EN 55035:2017
REPORT VERSION	0	V1.0

Attestation of Global Compliance (Shenzhen) Co., Ltd

CAUTION:

This report shall not be reproduced except in full without the written permission of the test laboratory and shall not be quoted out of context.







Report No.: AGC02862190602EE03 Page 2 of 55

Report Revise Record

Report Version	Revise Time	Issued Date	Valid Version	Notes
V1.0		Jul. 08, 2019	Valid	Initial Release





TABLE OF CONTENTS

1. VERIFICATION OF CONFORMITY	
2. SYSTEM DESCRIPTION	6
3. MEASUREMENT UNCERTAINTY	
4. PRODUCT INFORMATION	
5. SUPPORT EQUIPMENT	
6. TEST FACILITY	9
7. EN 55032 LINE CONDUCTED EMISSION TEST	
7.1. LIMITS OF LINE CONDUCTED EMISSION TEST	
7.2. BLOCK DIAGRAM OF TEST SETUP	
7.3. PROCEDURE OF LINE CONDUCTED EMISSION TEST	
7.4. TEST RESULT OF LINE CONDUCTED EMISSION TEST	
8. EN 55032 RADIATED EMISSION TEST	17
8.1. LIMITS OF RADIATED DISTURBANCES	
8.2. BLOCK DIAGRAM OF TEST SETUP	
8.3. PROCEDURE OF RADIATED EMISSION TEST	
8.4. TEST RESULT OF RADIATED EMISSION TEST	
9. EN 61000-3-2 POWER HARMONICS TEST	
9.1. BLOCK DIAGRAM OF TEST SETUP	
9.2. RESULT	
10. EN 61000-3-3 VOLTAGE FLUCTUATION / FLICKER TEST	
10.1. LIMITS OF VOLTAGE FLUCTUATION AND FLICKER	
10.2. TEST PROCEDURE	
10.3. EUT OPERATING CONDITION	
10.4. BLOCK DIAGRAM OF TEST SETUP	
10.5. THE RESULT	
11. EN 61000-4-2 ESD IMMUNITY TEST	27
11.1. BLOCK DIAGRAM OF TEST SETUP	
11.2. TEST PROCEDURE	
11.3. PERFORMANCE	
12. EN 61000-4-3 RS IMMUNITY TEST	
12.1. BLOCK DIAGRAM OF TEST SETUP	
12.2. TEST PROCEDURE	
12.3. PERFORMANCE	
13. EN 61000-4-4 EFT IMMUNITY TEST	
13.1. BLOCK DIAGRAM OF TEST SETUP	
13.2. TEST PROCEDURE	





Report No.: AGC02862190602EE03 Page 4 of 55

13.3. PERFORMANCE	
14. EN 61000-4-5 SURGE IMMUNITY TEST	
14.1. BLOCK DIAGRAM OF TEST SETUP	
14.2. TEST PROCEDURE	
14.3. PERFORMANCE	
15. EN 61000-4-6 CS IMMUNITY TEST	
15.1. BLOCK DIAGRAM OF TEST SETUP	
15.2. TEST PROCEDURE	
15.3. PERFORMANCE	
16. EN 61000-4-8 PFMF TEST	
16.1. BLOCK DIAGRAM OF TEST SETUP	
16.2. TEST PROCEDURE	
17. EN 61000-4-11 DIPS IMMUNITY TEST	
17.1. BLOCK DIAGRAM OF TEST SETUP	
17.2. TEST PROCEDURE	
17.3. INTERPRETATION	
APPENDIX A: PHOTOGRAPHS OF TEST SETUP	
APPENDIX B: PHOTOGRAPHS OF EUT	





1. VERIFICATION OF CONFORMITY

Applicant	LEXIBOOK LIMITED				
Address	Unit 8-9, 4th Floor, Kenning Industrial Building, 19 Wang Hoi Road, Kowloon Bay, Kowloon, Hong Kong				
manufacturer LEXIBOOK LIMITED					
Address	Unit 8-9, 4th Floor, Kenning Industrial Building, 19 Wang Hoi Road, Kowloon Bay, Kowloon, Hong Kong				
Factory	LEXIBOOK LIMITED				
Address	Unit 8-9, 4th Floor, Kenning Industrial Building, 19 Wang Hoi Road, Kowloon Bay, Kowloon, Hong Kong				
Product Designation	Portable CD Player				
Brand Name	LEXIBOOK				
Test Model	RCD108				
Date of test	Jun. 28, 2019 to Jul. 05, 2019				
Deviation	None				
Test Result	Pass				
Report Template	AGCRT-EC-IT/AC				

The above equipment was tested by Attestation of Global Compliance (Shenzhen) Co., Ltd. for compliance with the requirements set forth in EU Directive and the Technical Standards mentioned above. This said equipment in the configuration described in this report shows the maximum emission levels emanating from equipment and the level of the immunity endurance of the equipment are within the compliance requirements. The test results of this report relate only to the tested sample identified in this report.

Tested By

Draven.li

Draven Li(Li Ming Liang)

Jul. 05, 2019

Reviewed By

Max Zhang

Max Zhang(Zhang Yi)

Jul. 08, 2019

Approved By

Forrest in

Forrest Lei(Lei Yonggang) Authorized Officer

Jul. 08, 2019





2. SYSTEM DESCRIPTION

NO.	TEST MODE DESCRIPTION	WORST
1	CD mode	V C
2	AUX mode	
3	MIC mode	

3. MEASUREMENT UNCERTAINTY

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in measurement" (GUM) published by ISO.

- Uncertainty of Conducted Emission, Uc = ±3.2 dB
- Uncertainty of Radiated Emission below 1GHz, Uc = ±3.9 dB
- Uncertainty of Radiated Emission above 1GHz, Uc = ±4.8 dB





4. PRODUCT INFORMATION

Power Supply

DC 9V by battery(6*1.5V) or AC 230V/50Hz

I/O Port Inform						
I/O Port of EUT						
I/O Port Type	Number	Cable Description	Tested With			
AUX In	1	00	1			
AC In	1	<u> </u>	10			
MIC In	- G1-	C	1			





5. SUPPORT EQUIPMENT

Device Type	Manufacturer	Model Name	Serial No.	Data Cable	Power Cable
Smartphone	Xiaomi	MI6	0 - c	0 - 0	-





Test Site	Attestation of Global Compliance (Shenzhen) Co., Ltd
Location	1-2/F, Building 19, Junfeng Industrial Park, Chongqing Road, Heping Community, Fuhai Street, Bao'an District, Shenzhen, Guangdong, China
Description	There is one 3m semi-anechoic an area test sites and two line conducted labs for final test. The chamber and the Line Conducted labs are constructed and calibrated to meet the FCC requirements in documents ANSI C63.4 and CISPR 32/EN 55032 requirements.

TEST EQUIPMENT OF CONDUCTED EMISSION TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
TEST RECEIVER	R&S	ESPI	101206	Jun.13, 2019	Jun.12, 2020
LISN	R&S	ESH2-Z5	100086	Jun.13, 2019	Jun.12, 2020

TEST EQUIPMENT OF RADIATED EMISSION TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
TEST RECEIVER	R&S	ESCI	10096	Jun.13, 2019	Jun.12, 2020
ANTENNA	SCHWARZBECK	VULB9168	D69250	Mar.01, 2018	Feb.28, 2020
Double-Ridged Waveguide Horn	ETS	3117	00034609	Mar.01, 2018	Feb.28, 2020
Broadband Preamplifier	SCHWARZBECK	VULB9168	D69250	Jun.13, 2019	Jun.12, 2020

TEST EQUIPMENT OF POWER HARMONICS / VOLTAGE FLUCTUATION / FLICKER TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Signal Conditioning Unit	Schaffner	CCN1000-1	72431	Aug.19, 2018	Aug.18, 2019
AC Source	Schaffner	NSG1007	56825	Aug.19, 2018	Aug.18, 2019

TEST EQUIPMENT OF SURGE/EFT/DIPSTEST

Description	Manufacturer	Model	Model S/N		Cal. Due
EFT、Surge Generator	Schaffner	Modula 6150	34437	Aug.19, 2018	Aug.18, 2019

TEST EQUIPMENT OF ESD TEST

Equipment	Manufacturer	Model	S/N Cal. Date		Cal. Due
ESD Simulator	TESEQ	NSG 438	1509	Jun.13, 2019	Jun.12, 2020



 $\label{eq:attestation} Attestation of Global Compliance (Shenzhen) Co., Ltd.$



TEST EQUIPMENT OF RS IMMUNITY TEST

Description	Manufacturer	Model	S/N	Cal. Date	Cal. Due
SIGNAL GENERATOR	BAS		MY43351603	May.13, 2019	May.12, 2020
POWER SENSOR	R&S	URV5-Z4	100124	May.13, 2019	May.12, 2020
POWER METER	R&S	NRVD	832378/027	Jun.13, 2019	Jun.12, 2020
POWER AMPLIFIER	KALMUS	7100LC	04-02/17-06-001	Jun.13, 2019	Jun.12, 2020
RF AMPLIFIER	Milmega	AS0104- 55_55	1004793	Jun.13, 2019	Jun.12, 2020
Double-Ridged Waveguide Horn	ETS	3117			May.15, 2021
Broadband Preamplifier	SCHWARZBEC K	VULB9168 D69250		Mar.01, 2018	Feb.28, 2020

TEST EQUIPMENT OF CS IMMUNITY TEST

Manufacturer	Model	S/N	Cal. Date	Cal. Due			
AR	75A250	18464	Jun.10, 2019	Jun.09, 2020			
Schaffner	M016	21614	Aug.19, 2018	Aug.18, 2019			
6dB attenuator JWF		N/A	Jun.10, 2019	Jun.09, 2020			
Luthi	EM101			35773	Aug.19, 2018	Aug.18, 2019	
R&S	URV5-Z4	100124	May.13, 2019	May.12, 2020			
R&S	NRVD	8323781027	Jun.10, 2019	Jun.09, 2020			
R&S	E4421B	MY43351603	May.13, 2019	May.12, 2020			
	AR Schaffner JWF Luthi R&S R&S	AR75A250SchaffnerM016JWF50FHC- 006-50LuthiEM101R&SURV5-Z4R&SNRVD	AR 75A250 18464 Schaffner M016 21614 JWF 50FHC- 006-50 N/A Luthi EM101 35773 R&S URV5-Z4 100124 R&S NRVD 8323781027	AR 75A250 18464 Jun.10, 2019 Schaffner M016 21614 Aug.19, 2018 JWF 50FHC- 006-50 N/A Jun.10, 2019 Luthi EM101 35773 Aug.19, 2018 R&S URV5-Z4 100124 May.13, 2019 R&S NRVD 8323781027 Jun.10, 2019			





7. EN 55032 LINE CONDUCTED EMISSION TEST

7.1. LIMITS OF LINE CONDUCTED EMISSION TEST

EN 55032 Table clause	Frequency range (MHz)	Coupling device	Detector type / bandwidth	Class B limits (dBuV)
	0.15 - 0.5		66 - 56	
A10.1	0.5 - 5		Quasi-peak / 9kHz	56
Nº . G	5 - 30.0			60
	0.15 - 0.5	AMN/LISN		56 - 46
A10.1	0.5 - 5		Average / 9kHz	46
	5 - 30.0		~G ⁰	50

Note:

1. The lower limit shall apply at the transition frequency.

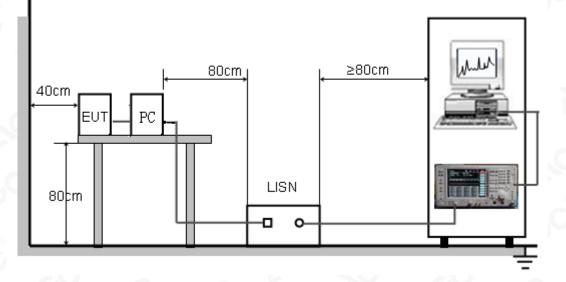
2. The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.50MHz.

AT TELECOMMUNICATION PORT

F	Maximum RF Line Voltage				
Frequency	Q.P.(dBuV)	Average(dBuV)			
150kHz-500kHz	84-74	74-64			
500kHz-30MHz	74	64			

NOTE 2 The current and voltage disturbance limits are derived for use with an impedance stabilization network (ISN) which presents a common mode (asymmetric mode) impedance of 150 Ω to the telecommunication port under test (conversion factor is 20 log10 150 / I = 44 dB).

7.2. BLOCK DIAGRAM OF TEST SETUP







7.3. PROCEDURE OF LINE CONDUCTED EMISSION TEST

- (1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN55032 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- (2) Support equipment, if needed, was placed as per EN55032.
- (3) All I/O cables were positioned to simulate typical actual usage as per EN55032.
- (4) The EUT received AC230V/50Hz power through a Line Impedance Stabilization Network (LISN/AMN) which supplied power source and was grounded to the ground plane.
- (5) All support equipments received power from a second LISN supplying power of AC 230V/50Hz, if any.
- (6) The EUT test program was started. Emissions were measured on each current carrying line of the EUT using a spectrum Analyzer / Receiver connected to the LISN powering the EUT. The LISN has two monitoring points: Line 1 (Hot Side) and Line 2 (Neutral Side). Two scans were taken: one with Line 1 connected to Analyzer / Receiver and Line 2 connected to a 50 ohm load; the second scan had Line 1 connected to a 50 ohm load and Line 2 connected to the Analyzer / Receiver.
- (7) Analyzer / Receiver scanned from 150 kHz to 30 MHz for emissions in each of the test modes.
- (8) During the above scans, the emissions were maximized by cable manipulation.
- (9) A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions.
- (10) Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less –2dB to the A.V. limit in Peak mode, then the emission signal was re-checked using Q.P and Average detector.

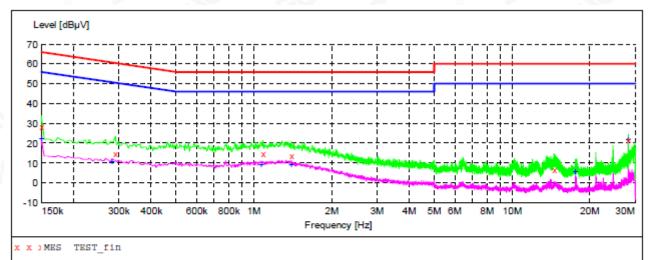
Note: The test modes were carried out for all operation modes The worst case (Mode 1) was showed as the follow:



7.4. TEST RESULT OF LINE CONDUCTED EMISSION TEST

GC

LINE CONDUCTED EMISSION TEST-L



MEASUREMENT RESULT: "TEST fin"

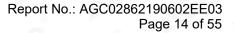
6/21/2019 9:4	2PM						
Frequency	Level	Transd	Limit	Margin	Detector	Line	PE
MHz	dBµV	dB	dBµV	dB			
0.150000	28.30	10.8	66	37.7	QP	L1	FLO
0.290000	15.20	10.9	61	45.3	QP	L1	FLO
1.082000	14.60	11.4	56	41.4	QP	L1	FLO
1.394000	14.10	11.5	56	41.9	QP	L1	FLO
14.558000	6.90	12.1	60	53.1	QP	L1	FLO
28.226000	22.10	12.8	60	37.9	QP	L1	FLO

MEASUREMENT RESULT: "TEST fin2"

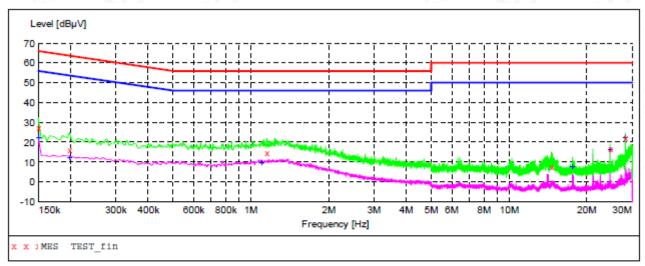
6/21/2019 9:	42PM						
Frequency	Level	Transd	Limit	Margin	Detector	Line	PE
MHz	dBµV	dB	dBµV	dB			
0.150000	22.60	10.8	56	33.4	AV	L1	FLO
0.282000	10.80	10.9	51	40.0	AV	L1	FLO
1.066000	9.40	11.4	46	36.6	AV	L1	FLO
1.394000	9.00	11.5	46	37.0	AV	L1	FLO
17.594000	5.50	12.3	50	44.5	AV	L1	FLO
28.226000	21.90	12.8	50	28.1	AV	L1	FLO

RESULT: PASS





LINE CONDUCTED EMISSION TEST-N



MEASUREMENT RESULT: "TEST fin"

6/21/2019 9:4	6PM						
Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line	PE
0.150000	27.80	10.8	66	38.2	QP	N	FLO
0.198000	16.50	10.9	64	47.2	QP	N	FLO
1.154000	14.70	11.5	56	41.3	OP	N	FLO
14.590000	7.80	12.1	60	52.2	ÕP	N	FLO
24,682000	16.90	12.7	60	43.1	ÕP	N	FLO
28.226000	22.40	12.8	60	37.6	Q₽	N	FLO

MEASUREMENT RESULT: "TEST fin2"

6,	/21/2019 9:4			T		Detector	T. d.	
	Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line	PE
	0.150000	22.40	10.8	56	33.6	AV	N	FLO
	0.198000	12.40	10.9	54	41.3	AV	N	FLO
	1.102000	9.60	11.5	46	36.4	AV	N	FLO
	17.590000	7.60	12.3	50	42.4	AV	N	FLO
	24.682000	16.40	12.7	50	33.6	AV	N	FLO
	28.226000	22.20	12.8	50	27.8	AV	N	FLO

RESULT: PASS

AGC®



8. EN 55032 RADIATED EMISSION TEST 8.1. LIMITS OF RADIATED DISTURBANCES

Radiated Emission at Frequencies up to 1GHz

For Class B	Fauipment	SAC/OATS
	Equipritorit	0/10/0/110

EN 55032 Table clause	Frequency range (MHz)	Distance (m)	Detector type	Limits (dBuV/m)
A4.1	30 - 230	10	Quasi Dask	30
A4.1	230 - 1000	10	Quasi Peak	37
A4 2	30 - 230	2	Quasi Dask	40
A4.2	230 - 1000	3 _ 0	Quasi Peak	47

Radiated Emission at Frequencies above 1GHz

For Class B Equipment FSOATS

EN 55032 Table clause	Frequency range (MHz)	Distance (m)	Detector type	Limits (dBuV/m)
	1000 - 3000	0	Average	50
A5.1	3000 - 6000	200	Average	54
	1000 - 3000	3	Deak	70
A5.2	3000 - 6000	0	Peak	74

Note: The lower limit shall apply at the transition frequency.

Required highest frequency for radiated measurement

itequireu ingile		
EN 55032 Table clause	Highest internal frequency (Fx)	Highest measured frequency
0	Fx ≦ 108 MHz	1 GHz
	108 MHz < Fx ≦ 500 MHz	2 GHz
	500 MHz $<$ Fx \leq 1 GHz	5 GHz
	Fx > 1	5 x Fx up to a maximum of 6 GHz

NOTE 1 For TV and FM broadcast receivers, Fx is determined from the highest frequency generated or used excluding the local oscillator and tuned frequencies.

NOTE 2 Fx is highest fundamental frequency generated or used within the EUT or highest frequency at which it operates.

Where Fx is unknown, the radiated emission measurements shall be performed up to 6 GHz.

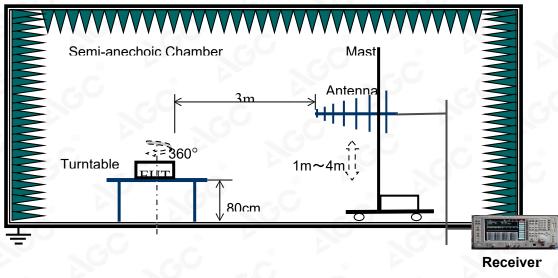




8.2. BLOCK DIAGRAM OF TEST SETUP

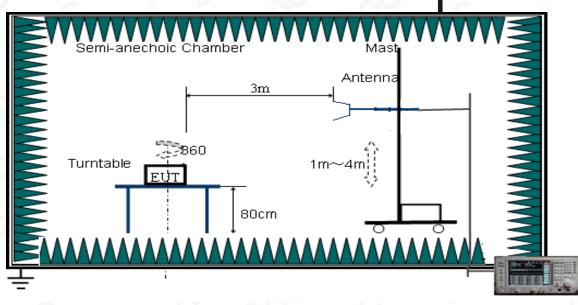
System Diagram of Connections between EUT and Simulators

Radiated Disturbance 30M to1 GHz



Note: The resolution bandwidth and video bandwidth of test receiver/spectrum analyzer is 120kHz for quasi-peak detection (QP) at frequency up to 1GHz.

Radiated Disturbance above 1 GHz



Receiver

Note: The resolution bandwidth of test receiver/spectrum analyzer is 1MHz and video bandwidth is 3MHz for Peak detection (PK) at frequency above 1GHz. The resolution bandwidth of test receiver/spectrum analyzer is 1 MHz for Average detection (AV) at frequency above 1GHz.

For the actual test configuration, please refer to the related item - Photographs of the Test Configuration.



AGC[®]

8.3. PROCEDURE OF RADIATED EMISSION TEST

- (1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane as per EN 55032 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- (2) Support equipment, if needed, was placed as per EN 55032.
- (3) All I/O cables were positioned to simulate typical actual usage as per EN 55032.
- (4) The EUT received AC230V/50Hz power through the outlet socket under the turntable. All support equipments received AC230V/50Hz power from socket under the turntable, if any.
- (5) The antenna was placed at 3 meter away from the EUT as stated in EN 55032. The antenna connected to the Analyzer via a cable and at times a pre-amplifier would be used.
- (6) The Analyzer / Receiver quickly scanned from 30MHz to 1000MHz. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- (6) The Analyzer / Receiver quickly scanned from 1GHz to 6000MHz. The EUT test program was started.
- (7) The test mode(s) were scanned during the test:
- (8) Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and Q.P./Peak reading is presented.

Note: The test modes were carried out for all operation modes The worst case (Mode 1) was showed as the follow:

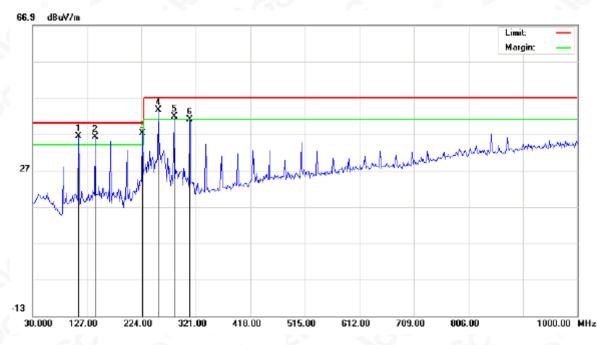


8.4. TEST RESULT OF RADIATED EMISSION TEST

R

AGC

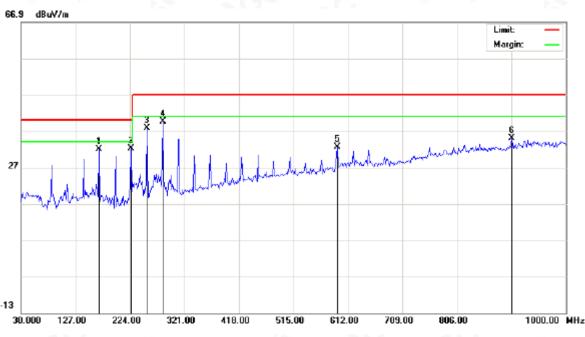
RADIATED EMISSION BELOW 1GHZ-HORIZONTAL



	No.	Mk	Freq.	Reading	Factor	Measurement	Limit	Over	Detector	Antenna Height	Table Degree	Comment
		•	MHz	dBuV	dB/m	dBuV/m	dBuV/m	dB		cm	degree	
	1	İ	112.4500	19.14	17.23	36.37	40.00	-3.63	peak			
	2	İ	141.5500	16.95	19.23	36.18	40.00	-3.82	peak			
	3	*	225.8043	19.60	17.65	37.25	40.00	-2.75	QP			
	4	İ	254.7167	25.23	18.40	43.63	47.00	-3.37	peak			
	5	İ	282.2000	21.99	19.89	41.88	47.00	-5.12	peak			
[6	İ	309.6833	21.25	19.81	41.06	47.00	-5.94	peak			







RADIATED EMISSION BELOW 1GHZ- VERTICAL

No.	Mk	Freq.	Reading	Factor	Measurement	Limit	Over	Detector	Antenna Height	Table Degree	Comment
	•	MHz	dBuV	dB/m	dBuV/m	dBuV/m	dB		cm	degree	
1		169.0333	13.67	18.26	31.93	40.00	-8.07	peak			
2		225.6167	14.57	17.64	32.21	40.00	-7.79	peak			
3		254.7167	19.32	18.40	37.72	47.00	-9.28	peak			
4	*	282.2000	19.64	19.89	39.53	47.00	-7.47	peak			
5		592.6000	5.85	26.80	32.65	47.00	-14.35	peak			
6		903.0000	3.35	31.73	35.08	47.00	-11.92	peak			

RESULT: PASS

Remark: which above 1GHz are attenuated more than 20dB below the permissible limits or the field strength is too small to be measured.



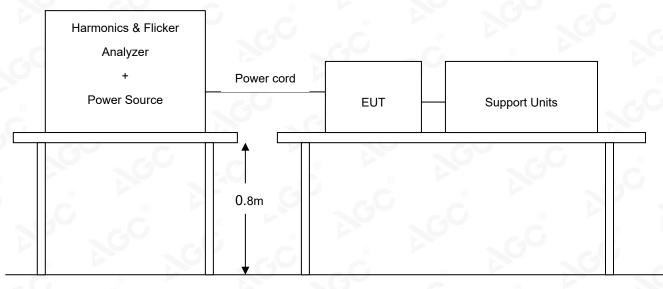


9. EN 61000-3-2 POWER HARMONICS TEST

POWER HARMONICS	MEASUREMENT

Port	AC mains
Basic Standard	EN 61000-3-2
Product Standard	EN 55035
Limits	CLASS A ; CLASS B ; CLASS C; CLASS D
Tester	Max
Temperature	25.0°C
Humidity	55.0%

9.1. BLOCK DIAGRAM OF TEST SETUP



9.2. RESULT

Note: Owning to the power of EUT is less than 75W, so test is not applicable.





10. EN 61000-3-3 VOLTAGE FLUCTUATION / FLICKER TEST

VOLTAGE FLUCTUATION/FLICKER MEASUREMENT

Port	AC mains
Basic Standard	EN 61000-3-3
Product Standard	EN 55035
Limits	§5 of EN 61000-3-3
Tester:	Max
Temperature	25.0°C
Humidity	55.0%

10.1. LIMITS OF VOLTAGE FLUCTUATION AND FLICKER

Tests	Li	mits	Descriptions
Tesis	IEC555-3	IEC/EN 61000-3-3	Descriptions
Pst	≤ 1.0, Tp= 10 min.	≤ 1.0, Tp= 10 min.	Short Term Flicker Indicator
Plt	N/A	≤ 0.65, Tp=2 hr.	Long Term Flicker Indicator
dc	≤ 3 %	≤ 3.3 %	Relative Steady-State ∨-Chang
dmax	≤4%	$\leq 4\%$	Maximum Relative ∨-change
d (t)	N/A	\leq 3.3% for $>$ 500 ms	Relative V-change characteristic

10.2. TEST PROCEDURE

a. Harmonic Current Test:

Test was performed according to the procedures specified in Clause 5.0 of IEC555-2 and/or Sub-clause 6.2 of IEC/EN 61000-3-2 depend on which standard adopted for compliance measurement.

b. Fluctuation and Flickers Test:

Tests was performed according to the Test Conditions/Assessment of Voltage Fluctuations specified in Clause 5.0/6.0 of IEC555-3 and/or Clause 6.0/4.0 of IEC/EN 61000-3-3 depend on which standard adopted for compliance measurement.

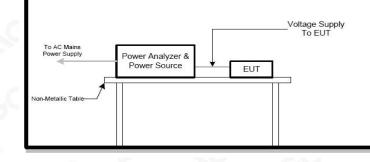
c. All types of harmonic current and/or voltage fluctuation in this report are assessed by direct measurement using flicker-meter.

d. For the actual test configuration, please refer to the related Item -EUT Test Photos.

10.3. EUT OPERATING CONDITION

The EUT tested system was configured as the statements of **2.2** Unless otherwise a special operating condition is specified in the follows during the testing.

10.4. BLOCK DIAGRAM OF TEST SETUP







10.5. THE RESULT

Note: The test modes were carried out for all operation modes

The worst case _ MODE 1(By Adapter Charging) was showed as the follow:

Flicker Test Summary per EN/EN 61000-3-3 (Run time)

Parameter values recorded during the test:

Test Parameter	Measurement Value	Limit	Remarks
P _{st}	0.79	1.0	Pass
Pit	0.47	0.65	Pass
T _{dt(s)}	0.33	0.5	Pass
d _{max} (%)	2.889%	4%	Pass
d _c (%)	1.341%	3.3%	Pass





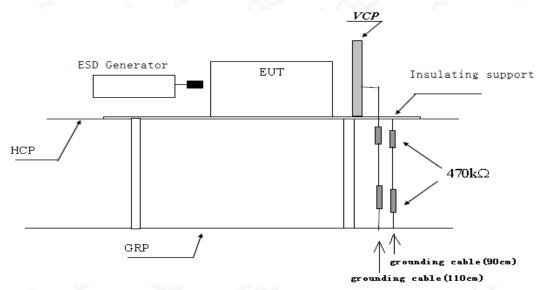
11. EN 61000-4-2 ESD IMMUNITY TEST

ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

Port	Enclosure
Basic Standard	EN 61000-4-2
Product Standard	EN 55035
Test Level	± 8.0 kV (Air Discharge) ± 4.0 kV (Contact Discharge) ± 4.0 kV (Indirect Discharge)
Standard require	В
Tester	Мах
Temperature	25.0C
Humidity	55.0%

11.1. BLOCK DIAGRAM OF TEST SETUP

(The 470 k ohm resistors are installed per standard requirement)





AGC[®]

11.2. TEST PROCEDURE

The EUT was located 0.1 m minimum from all side of the HCP.

The support units were located 1 m minimum away from the EUT.

EUT worked with resistance load, and make sure EUT worked normally.

Active the communication function if the EUT with such port(s).

As per the requirement of EN 55035; applying direct contact discharge at the sides other than front of EUT at minimum 50 discharges (25 positive and 25 negative) if applicable, can't be applied direct contact discharge side of EUT then the indirect discharge shall be applied. One of the test points shall be subjected to at least 50 indirect discharge (contact) to the front edge of horizontal coupling plane.

Other parts of EUT where it is not possible to perform contact discharge then selecting appropriate points of EUT for air discharge, a minimum of 10 single air discharges shall be applied.

The application of ESD to the contact of open connectors is not required.

Note: As per the A2 to EN 61000-4-2, a bleed resistor cable is connected between the EUT and HCP during the test.

TEST RESULT:

Note: The test modes were carried out for all operation modes

The worst case _Mode 1 (by adapter charging) was showed as the follow:

Voltage	Coupling	Test Performance	Performance Result	Result (Pass/Fail)
±2kV; ±4kV	Contact Discharge	No function loss	A	Pass
±2kV; ±4kV	Indirect Discharge HCP (Front)	No function loss	A	Pass
±2kV; ±4kV	Indirect Discharge HCP (Left)	No function loss	A	Pass
±2kV; ±4kV	Indirect Discharge HCP (Back)	No function loss	A	Pass
±2kV; ±4kV	Indirect Discharge HCP (Right)	No function loss	A	Pass
±2kV; ±4kV	Indirect Discharge VCP (Front)	No function loss	А	Pass
±2kV; ±4kV	Indirect Discharge VCP (Left)	No function loss	A	Pass
±2kV; ±4kV	Indirect Discharge VCP (Back)	No function loss	A	Pass
±2kV; ±4kV	Indirect Discharge VCP (Right)	No function loss	A	Pass
±2kV; ±4kV; ±8kV	Air Discharge	No function loss	А	Pass







11.3. PERFORMANCE

⊠Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
☐Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

|| PASS



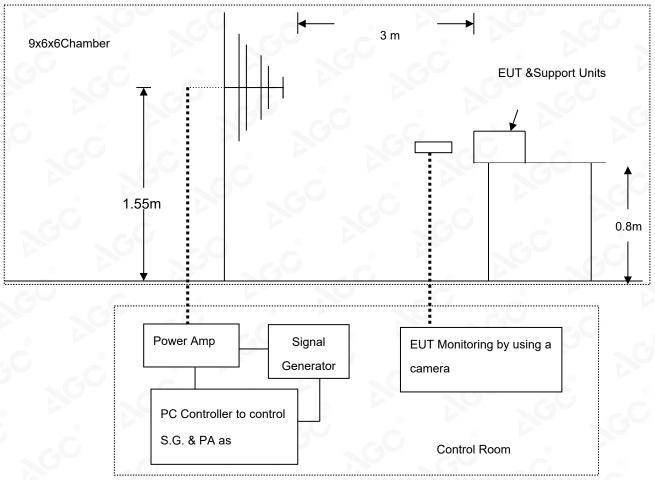


12. EN 61000-4-3 RS IMMUNITY TEST

RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

Port	Enclosure
Basic Standard	EN 61000-4-3
Product Standard	EN 55035
Test Level:	3V/m with 80% AM. 1kHz Modulation.
Standard require	A
Tester	Max
Temperature	25.0°C
Humidity	55.0%

12.1. BLOCK DIAGRAM OF TEST SETUP







12.2. TEST PROCEDURE

The EUT was located at the edge of supporting table keep 3 meter away from transmitting antenna, it just the calibrated square area of field uniformity. The support units were located outside of the uniformity area, but the cable(s) connected with EUT were exposed to the calibrated field as per EN 61000-4-3.

EUT worked with resistance load, and make sure EUT worked normally.

Setting the testing parameters of RS test software perEN 61000-4-3.

Performing the test at each side of with specified level (3V/m) at 1% steps and test frequency from 80MHz to

1000MHz , 1,8 GHz, 2,6 GHz, 3,5 GHz,5 GHz.

Recording the test result in following table.

EN 61000-4-3 Final test conditions:

Test level: 3V/m

Steps: 1 % of fundamental

Dwell Time: 1 sec

TEST RESULT:

Note: The test modes were carried out for all operation modes

The worst case _ Mode 1(by adapter charging) was showed as the follow:

Range (MHz)	Field	Modulation	Polarity	Position	Test Performance	Performance Result	Result (Pass/Fail)
80-1000	3V/m	AM	н	Front	No function loss	A	Pass
80-1000	3V/m	AM	нС	Left	No function loss	A	Pass
80-1000	3V/m	AM	н	Back	No function loss	G A	Pass
80-1000	3V/m	AM	н	Right	No function loss	A	Pass
80-1000	3V/m	AM	V	Front	No function loss	A	Pass
80-1000	3V/m	AM	V	Left	No function loss	A	Pass
80-1000	3V/m	AM	V	Back	No function loss	A	Pass
80-1000	3V/m	AM	V	Right	No function loss	A	Pass
1800	3V/m	AM	Н	Front	No function loss	A	Pass
1800	3V/m	AM	Н	Left	No function loss	AG	Pass
1800	3V/m	AM	Н	Back	No function loss	A	Pass
1800	3V/m	AM	Н	Right	No function loss	A	Pass
1800	3V/m	AM	V	Front	No function loss	А	Pass
1800	3V/m	AM	V	Left	No function loss	А	Pass
1800	3V/m	AM	V	Back	No function loss	А	Pass
1800	3V/m	AM	V	Right	No function loss	A	Pass
2600	3V/m	AM	н	Front	No function loss	А	Pass
2600	3V/m	AM	н	Left	No function loss	A	Pass



Attestation of Global Compliance(Shenzhen)Co.,Ltd.

Add: 2/F., Building 2, No.1–4, Chaxi Sanwei Technial Industrial Park, Gushu,

Pass	A	No function loss	Back	Н	AM	3V/m	2600
Pass	А	No function loss	Right	Н	AM	3V/m	2600
Pass	А	No function loss	Front	V	АМ	3V/m	2600
Pass	Α	No function loss	Left	V	AM	3V/m	2600
Pass	А	No function loss	Back	V	AM	3V/m	2600
Pass	CA	No function loss	Right	V	AM	3V/m	2600
Pass	A	No function loss	Front	н	AM	3V/m	3500
Pass	А	No function loss	Left	н	AM	3V/m	3500
Pass	A	No function loss	Back	Н	AM	3V/m	3500
Pass	А	No function loss	Right	Н	AM	3V/m	3500
Pass	A	No function loss	Front	V	AM	3V/m	3500
Pass	A	No function loss	Left	V	AM	3V/m	3500
Pass	A	No function loss	Back	V	AM	3V/m	3500
Pass	А	No function loss	Right	V	AM	3V/m	3500
Pass	A	No function loss	Front	н	AM	3V/m	5000
Pass	A	No function loss	Left	HC	AM	3V/m	5000
Pass	G A	No function loss	Back	н	AM	3V/m	5000
Pass	A	No function loss	Right	н	AM	3V/m	5000
Pass	A	No function loss	Front	V	AM	3V/m	5000
Pass	A	No function loss	Left	V	AM	3V/m	5000
Pass	Α	No function loss	Back	V	AM	3V/m	5000
Pass	А	No function loss	Right	V	AM	3V/m	5000





Report No.: AGC02862190602EE03 Page 29 of 55

12.3. PERFORMANCE

⊠Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
☐Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

PASS

FAIL





13. EN 61000-4-4 EFT IMMUNITY TEST

ELECTRICAL FAST TRANSIENTS/BURST IMMUNITY TEST

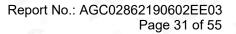
Port	On Power Supply Lines ; On Telecommunication Port				
Basic Standard	EN 61000-4-4				
Product Standard	EN 55035				
Test Level	+/- 1kV for Power Supply Lines; +/- 0.5kV for LAN Lines;				
Standard require	В				
Tester	Max				
Temperature	25.0C				
Humidity	55.0%				

13.1. BLOCK DIAGRAM OF TEST SETUP

		EUT	Support Units	
AC Line EFT/Burst/Surge Generator	80cm	Non-Con	ductive Table	

Controller Computer







13.2. TEST PROCEDURE

The EUT and support units were located on a wooden table 0.8m away from ground reference plane.

A 1.0 meter long power cord was attached to EUT during the test.

The length of communication cable between communication port and clamp was keeping within 1 meter.

EUT worked with resistance load, and make sure EUT worked normally.

Related peripherals work during the test.

Recording the test result as shown in following table.

Test conditions:

Impulse Frequency: 5 kHz

Tr/Th: 5/50ns

Burst Duration: 15ms

Burst Period: 300ms

TEST RESULT:

Note: The test modes were carried out for all operation modes The worst case _ Mode 1(By Adapter Charging) was showed as the follow:

Inject Line	Voltage kV	Inject Method	Test Performance	Performance Result	Result (Pass/Fail)
a.c. port, L	+/- 1	Direct	No function loss	А	Pass
a.c. port, N	+/- 1	Direct	No function loss	A	Pass
a.c. port, L-N	+/- 1	Direct	No function loss	А	Pass
a.c. port, PE	+/- 1	Direct	No function loss	A	Pass
a.c. port, L-PE	+/- 1	Direct	No function loss	A	Pass
a.c. port, N-PE	+/- 1	Direct	No function loss	A	Pass
a.c. port, L-N-PE	+/- 1	Direct	No function loss	A	Pass

13.3. PERFORMANCE

⊠Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

⊠PASS □FAIL

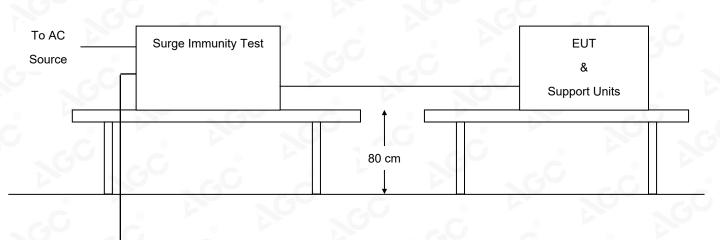




14. EN 61000-4-5 SURGE IMMUNITY TEST

SURGE IMMUNITY	TEST
Port	On Power Supply Lines ; On Telecommunication Port
Basic Standard	EN 61000-4-5
Product Standard	EN 55035
Requirements	+/- 1kV (Line to Line) On Power Supply Lines +/- 1kV (Line to Line) On LAN Lines
Standard require	В
Tester	Max
Temperature	25.0°C
Humidity	55.0%

14.1. BLOCK DIAGRAM OF TEST SETUP



100	
	Controller Computer





14.2. TEST PROCEDURE

The EUT and support units were located on a wooden table 0.8 m away from ground floor. EUT worked with resistance load, and make sure EUT worked normally.

Recording the test result as shown in following table.

Test conditions:

Voltage Waveform	1.2/50 <i>u</i> s
Current Waveform	8/20 <i>u</i> s
Polarity	Positive/Negative
Phase angle	0°,180°, 90°, 270°
Number of Test	5

TEST RESULT:

Note: The test modes were carried out for all operation modes The worst case _ Mode 1(By Adapter Charging) was showed as the follow:

Coupling Line	Voltage (kV)	Polarity	Coupling Method	Test Performance	Performance Result	Result (Pass/Fail)
a.c. power, L-N	<u> </u>	Positive/ Negative	Capacitive	No function loss	A	Pass
a.c. power, L-PE	2	Positive/ Negative	Capacitive	No function loss	А	Pass
a.c. power, N-PE	2	Positive/ Negative	Capacitive	No function loss	A	Pass





14.3. PERFORMANCE

⊠Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
☐Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
Criteria C:	

FAIL

PASS

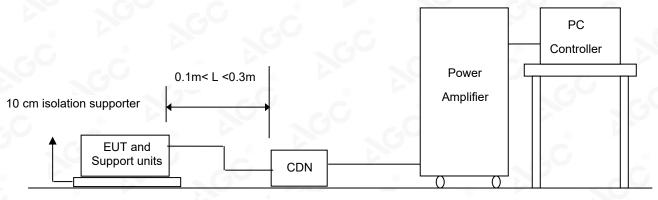




15. EN 61000-4-6 CS IMMUNITY TEST

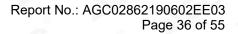
Port	On Power Supply Lines ; On Telecommunication Port				
Basic Standard	EN 61000-4-6				
Product Standard	EN 55035				
Requirements	0.15 MHz ~10MHz 3V with 80% AM. 1 kHz Modulation 10 MHz ~30MHz 3V to 1V with 80% AM. 1 kHz Modulation 30 MHz ~80MHz 1V with 80% AM. 1 kHz Modulation				
Standard require	A				
Tester	Мах				
Temperature	25.0°C				
Humidity	55.0%				

15.1. BLOCK DIAGRAM OF TEST SETUP



Ground Reference Plane







15.2. TEST PROCEDURE

The EUT and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.

EUT worked with resistance load, and make sure EUT worked normally.

Related peripherals work during the test.

Setting the testing parameters of CS test software per EN 61000-4-6.

Recording the test result in following table.

Test conditions:

Frequency Range	0.15MHz-80MHz
Frequency Step	1% of fundamental
Dwell Time	1 sec

TEST RESULT:

Note: The test modes were carried out for all operation modes The worst case _ MODE 1(By Adapter Charging) was showed as the follow:

Range (MHz)	Strength	Modulation	Performance Result	Result (Pass/Fail)
0.15-10	3V	AM	A	Pass
10-30	3V to 1V	AM	A	Pass
30-80	1V	AM	A	Pass





15.3. PERFORMANCE

⊠Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

⊠PASS □FAIL



16. EN 61000-4-8 PFMF TEST

POWER FREQUENCY MAGNETIC FIELDS IMMUNITY TEST

Port	Enclosure
Basic Standard	EN 61000-4-8
Product Standard	EN 55035
Requirements	50/60 Hz, 1A/m
Standard require	A
Tester	Мах
Temperature	25 °C
Humidity	55%

16.1. BLOCK DIAGRAM OF TEST SETUP

To AC	. Signal		EUT G	
Source	Generator		&	
			Support Units	
]
AGC		80 cm	GC C	
		80 cm	Support Units	-

Controller Computer	
7	





16.2. TEST PROCEDURE

The EUT shall be subjected to the test magnetic field by using the induction coil of standard dimensions $(1m \times 1m)$. The induction coil shall then be rotated by 90° in order to expose the EUT to the test field with different orientations.

Test Conditions:

Frequency	Polarity	Level	Test Performance	Performance Result	Result
50 Hz	X	1 A/m	No function loss		N/A
50 Hz	Y	1 A/m	No function loss	1	N/A
50 Hz	Z	1 A/m	No function loss		N/A

TEST RESULT:

N/A

Note: Owing to the EUT has no sensitive devices to PFMF, so it's not applicable.





17. EN 61000-4-11 DIPS IMMUNITY TEST

VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST

Port	On Power Supply Lines
Basic Standard	EN 61000-4-11
Product Standard	EN 55035
Requirements	0, 45, 90, 135, 180, 225, 270, 315 degrees
Test Interval	Min. 10 sec.
Tester	Max
Temperature	25.0°C
Humidity	55.0%

	Test Level % U _T	Reduction (%)	Duration (periods)	Performance Criteria
Voltage Dips	<5	>95	0.5	В
	70	30	25	С

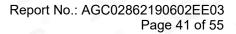
Voltage	Test Level	Reduction	Duration	Performance
	% U _T	(%)	(periods)	Criteria
Interruptions	<5	>95	250	С

17.1. BLOCK DIAGRAM OF TEST SETUP

To AC	Dips/Interruption and Variations Simulator		EUT &
. GC_		200 20	Support Units
3°	ACC ACC	80 cm	200 200

Ö		C.C
0	Controller Computer	







17.2. TEST PROCEDURE

The EUT and support units were located on a wooden table, 0.8 m away from ground floor. EUT worked with resistance load, and make sure EUT worked normally.

Setting the parameter of tests and then perform the test software of test simulator.

Conditions changes to occur at 0 degree crossover point of the voltage waveform.

Recording the test result in test record form.

Test conditions:

The duration with a sequence of three dips/interruptions with interval of 10 s minimum (Between each test event)

TEST RESULT:

Note: The test modes were carried out for all operation modes

The worst case _ MODE 1(By Adapter Charging) was showed as the follow:

Voltage Dips:

Test Level % U _T	Reduction (%)	Duration (periods)	Observation	Performance Result	Result (Pass/Fail)
<5	>95	0.5	Normal	А	Pass
70	30	25	Normal	А	Pass

Voltage Interruptions:

Test Level % U _T	Reduction (%)	Duration (periods)	Observation	Performance Result	Result (Pass/Fail)
<5	>95	250	Stop charging	В	Pass





17.3. INTERPRETATION

⊠Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
⊠Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

PASS

FAIL





APPENDIX A: PHOTOGRAPHS OF TEST SETUP

LINE CONDUCTED EMISSION TEST SETUP



RADIATED EMISSION TEST SETUP





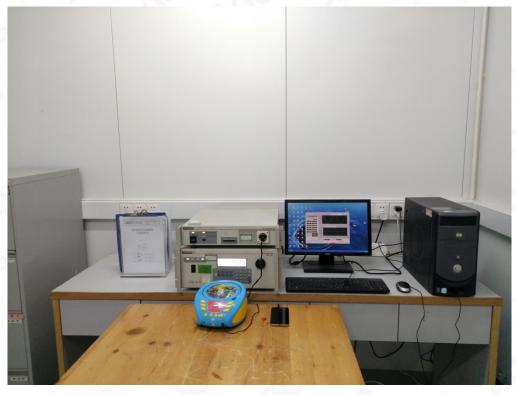


Report No.: AGC02862190602EE03 Page 44 of 55

EN 61000-4-2 ESD TEST SETUP



EN61000-3-3 VOLTAGE FLUCTUATION / FLICKER TEST SETUP

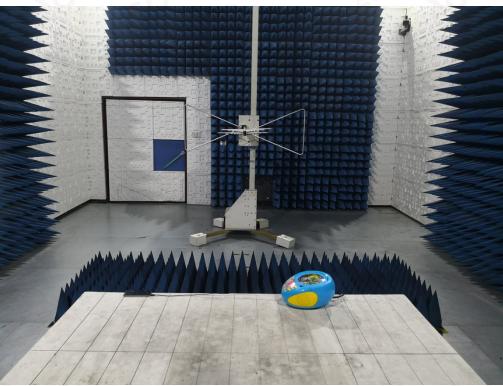






Report No.: AGC02862190602EE03 Page 45 of 55





EN 61000-4-6 CS IMMUNITY TEST SETUP





 $\label{eq:Attestation} Attestation of Global Compliance (Shenzhen) Co., Ltd.$



Report No.: AGC02862190602EE03 Page 46 of 55



EN 61000-4-4/-5/-11 EFT/SURGE/DIPS TEST SETUP

----END OF REPORT----



 $\label{eq:attestation} Attestation of Global Compliance (Shenzhen) Co., Ltd.$



Report No.: AGC02862190602EE03 Page 47 of 55

APPENDIX B: PHOTOGRAPHS OF EUT

ALL VIEW OF EUT





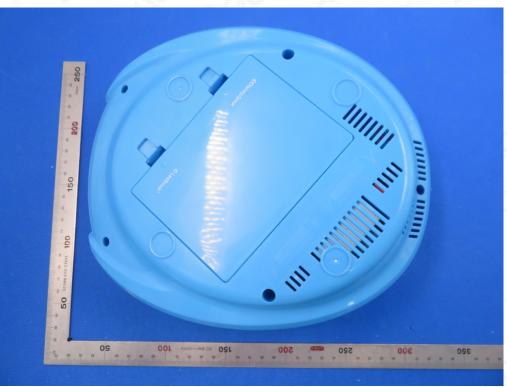


Report No.: AGC02862190602EE03 Page 48 of 55

TOP VIEW OF EUT



BOTTOM VIEW OF EUT







FRONT VIEW OF EUT



BACK VIEW OF EUT







LEFT VIEW OF EUT



RIGHT VIEW OF EUT

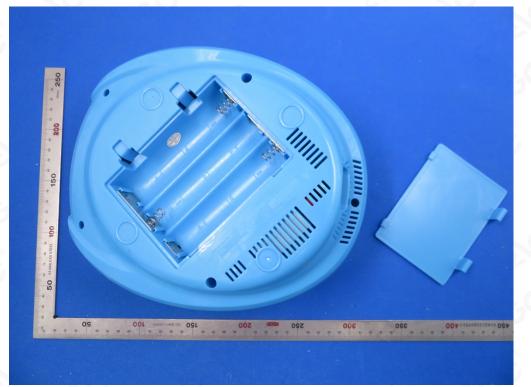




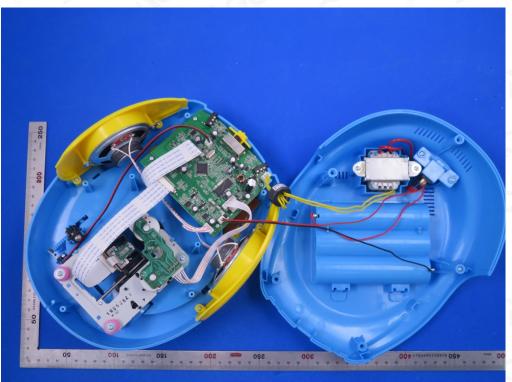
 $\label{eq:Attestation} Attestation of Global Compliance (Shenzhen) Co., Ltd.$



OPEN VIEW OF EUT-1



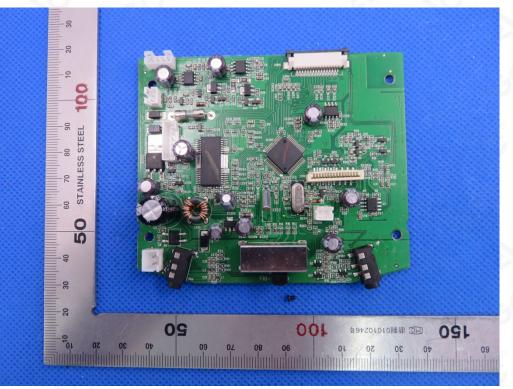
OPEN VIEW OF EUT-2



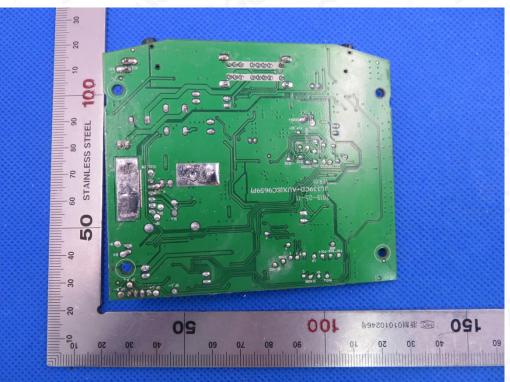




INTERNAL VIEW OF EUT-1



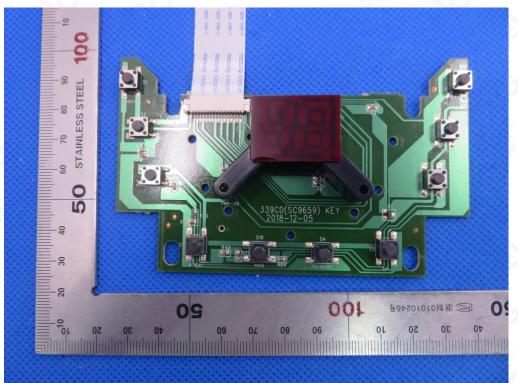
INTERNAL VIEW OF EUT-2



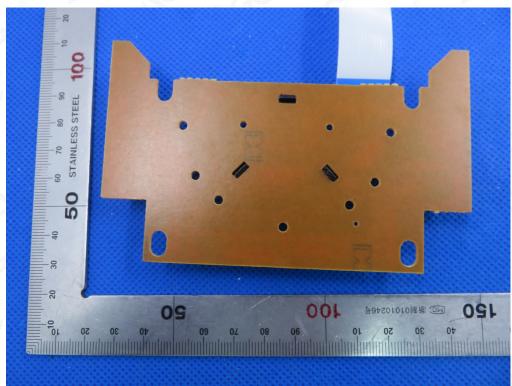




INTERNAL VIEW OF EUT-3



INTERNAL VIEW OF EUT-4





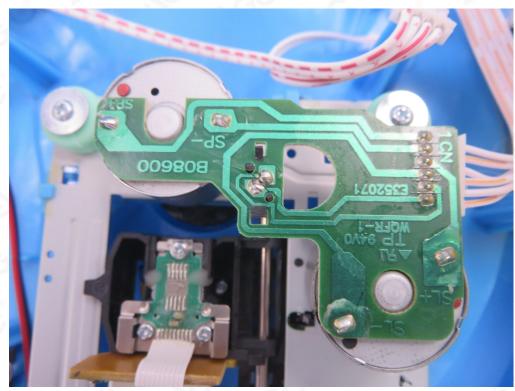


Report No.: AGC02862190602EE03 Page 54 of 55

INTERNAL VIEW OF EUT-5



INTERNAL VIEW OF EUT-6



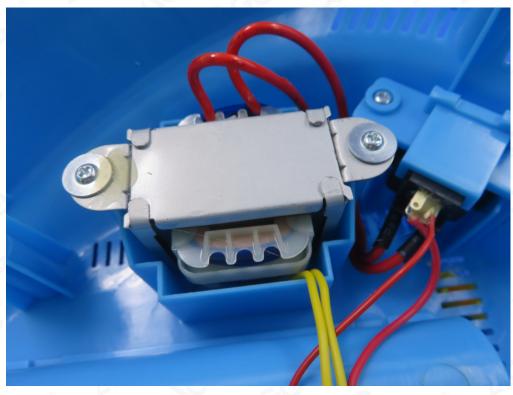




INTERNAL VIEW OF EUT-7



INTERNAL VIEW OF EUT-8



----END OF REPORT----

